FC12

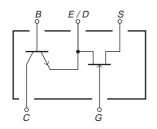


High-Frequency Amp, AM Applications, Low-Frequency Amp

Features

- · Composite type with 2 transistors contained in the CP package currently in use, improving the mounting efficiency greatly.
- The FC12 is formed with two chips, being equivalent to the 2SC4639, placed in one package.
- · Common drain and emitter.

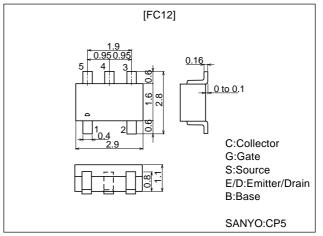
Electrical Connection



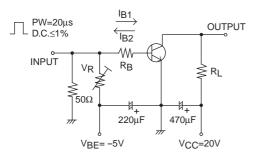
Package Dimensions

unit:mm

2075



Switching Time Test Circuit



10IB1 = -10IB2 = IC = 10mA

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Specifications

Absolute Maximum Ratings at $Ta = 25^{\circ}C$

Parameter	Symbol	Conditions	Ratings	Unit
[FET]				
Drain-to-Source Voltage	V _{DSX}		15	V
Gate-to-Drain Voltage	V _{GDS}		-15	V
Gate Current	IG		10	mA
Drain Current	ID		50	mA
Allowable Power Dissipation	PD		200	mW
[TR]	•			
Collector-to-Base Voltage	VCBO		55	V
Collector-to-Emitter Voltage	VCEO		50	V
Emitter-to-Base Voltage	V _{EBO}		6	V
Collector Current	Ic		150	mA
Collector Current (Pulse)	ICP		300	mA
Base Current	ΙB		30	mA
Collector Dissipation	PC		200	mW
[Common Ratings]				
Total Dissipation	PT		300	mW
Junction Temperature	Tj		150	°C
Storage Temperature	Tstg		-55 to +150	°C

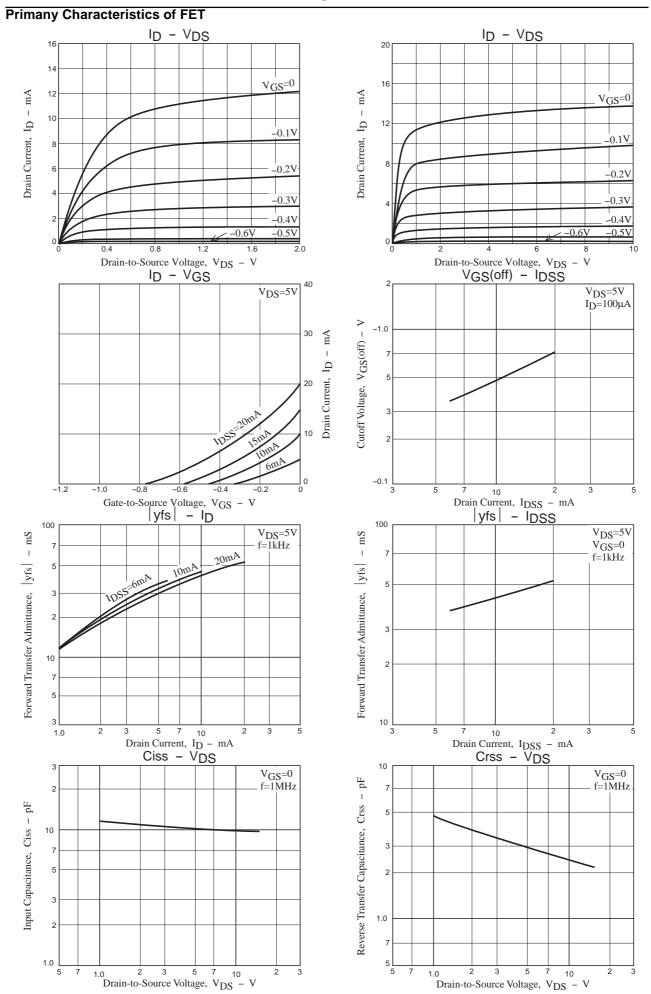
Marking:12

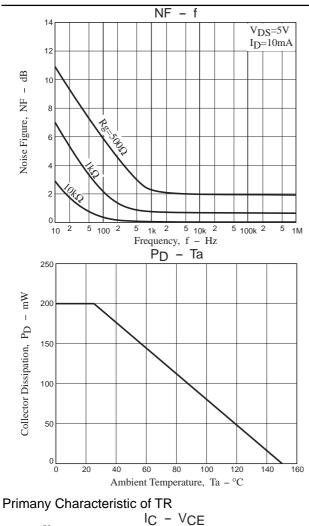
Electrical Characterisitics at Ta = 25°C

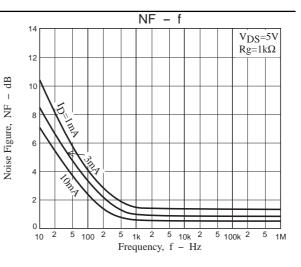
Parameter	Symbol	Conditions	Ratings			Unit
			min	typ	max	Offic
[FET]						
Gate-to-Drain Breakdown Voltage	V(BR)GDS	I_{G} =-10 μ A, V_{DS} =0	-15			V
Gate-to-Cutoff Current	IGSS	V _{GS} =-10V, V _{DS} =0			-1.0	nA
Cutoff Voltage	V _{GS(off)}	V _{DS} =5V, I _D =100μA	-0.2	-0.6	-1.4	V
Drain Current	IDSS	V _{DS} =5V, V _{GS} =0	6.0*		20.0*	mA
Forward Transfer Admittance	Y _{fs}	$V_{DS}=5V$, $V_{GS}=0$, $f=1kHz$	25	50		mS
Input Capacitance	Ciss	V_{DS} =5V, V_{GS} =0, f=1MHz		10		pF
Reverse Transfer Capacitance	Crss	V_{DS} =5V, V_{GS} =0, f=1MHz		3.0		pF
Noise Figure	NF	V_{DS} =5V, Rg=1k Ω , ID=1mA, f=1kHz		1.5		dB
[TR]						
Collector Cuttoff Current	ICBO	V _{CB} =35V, I _E =0			0.1	μΑ
Emitter Cutoff Current	I _{EBO}	V _{EB} =4V, I _C =0			0.1	μΑ
DC Current Gain	hFE	V _{CE} =6V, I _C =1mA	135		400	
Gain-Bandwidth Product	fΤ	V _{CE} =6V, I _C =10mA		200		MHz
Output Capacitance	Cob	V _{CB} =6V, f=1MHz		1.7		pF
C-E Saturation Voltage	V _{CE(sat)}	I _C =50mA, I _B =5mA		0.08	0.4	V
B-E Saturation Voltage	V _{BE(sat)}	I _C =50mA, I _B =5mA		0.8	1.0	V
C-B Breakdown Voltage	V(BR)CBO	I _C =10μA, I _E =0	55			V
C-E Breakdown Voltage	V(BR)CEO	I _C =1mA, R _{BE} =∞	50			V
E-B Breakdown Voltage	V(BR)EBO	I _E =10μA, I _C =0	6			V
Turn-ON Time	ton	See specified Test Circuit		0.15		μs
Storage Time	t _{stg}	See specified Test Circuit		0.75		μs
Fall Time	t _f	See specified Test Circuit		0.20		μs

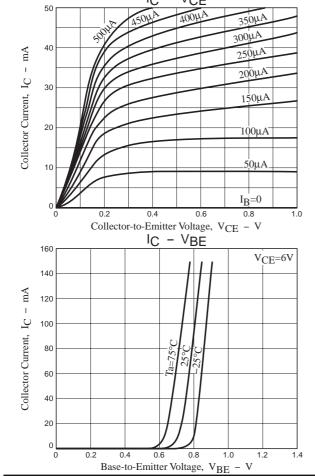
Note*:The FC12 is classified by $I_{\mbox{\footnotesize DSS}}$ as follows : (unit:mA).

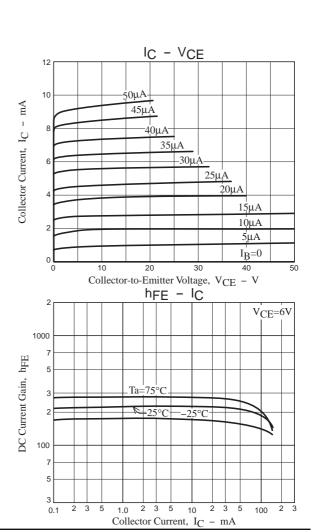
6.0 F 12.0	10.0 G 20.0
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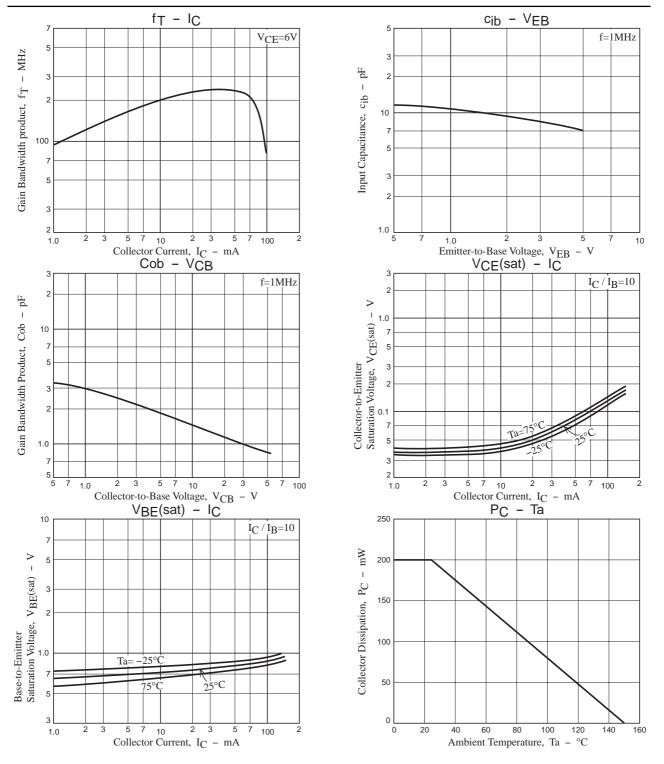












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